

**CAPACITANCE** (TA=25°C, f=1.0MHz)

| PARAMETER | SYMBOL | MIN. | MAX | UNIT |
|--------------------------|------------------|------|-----|------|
| Input Capacitance | C _{IN} | - | 8 | pF |
| Input/Output Capacitance | C _{I/O} | - | 10 | pF |

Note : These parameters are guaranteed by device characterization, but not production tested.

AC TEST CONDITIONS

| | |
|--|--|
| Input Pulse Levels | 0V to 3.0V |
| Input Rise and Fall Times | 3ns |
| Input and Output Timing Reference Levels | 1.5V |
| Output Load | C _L = 30pF, I _{OH} /I _{OL} = -4mA/8mA |

AC ELECTRICAL CHARACTERISTICS (V_{CC} = 5V±10%, TA = 0°C to 70°C)**(1) READ CYCLE**

| PARAMETER | SYMBOL | UT61256-8 | | UT61256-10 | | UT61256-12 | | UT61256-15 | | UNIT |
|------------------------------------|-------------------|-----------|------|------------|------|------------|------|------------|------|------|
| | | MIN. | MAX. | MIN. | MAX. | MIN. | MAX. | MIN. | MAX. | |
| Read Cycle Time | t _{RC} | 8 | - | 10 | - | 12 | - | 15 | - | ns |
| Address Access Time | t _{AA} | - | 8 | - | 10 | - | 12 | - | 15 | ns |
| Chip Enable Access Time | t _{ACE} | - | 8 | - | 10 | - | 12 | - | 15 | ns |
| Output Enable Access Time | t _{OE} | - | 4 | - | 5 | - | 6 | - | 7 | ns |
| Chip Enable to Output in Low Z | t _{CLZ*} | 2 | - | 2 | - | 3 | - | 4 | - | ns |
| Output Enable to Output in Low Z | t _{OLZ*} | 0 | - | 0 | - | 0 | - | 0 | - | ns |
| Chip Disable to Output in High Z | t _{CHZ*} | - | 4 | - | 5 | - | 6 | - | 7 | ns |
| Output Disable to Output in High Z | t _{OHZ*} | - | 4 | - | 5 | - | 6 | - | 7 | ns |
| Output Hold from Address Change | t _{OH} | 3 | - | 3 | - | 3 | - | 3 | - | ns |

(2) WRITE CYCLE

| PARAMETER | SYMBOL | UT61256-8 | | UT61256-10 | | UT61256-12 | | UT61256-15 | | UNIT |
|----------------------------------|-------------------|-----------|------|------------|------|------------|------|------------|------|------|
| | | MIN. | MAX. | MIN. | MAX. | MIN. | MAX. | MIN. | MAX. | |
| Write Cycle Time | t _{WC} | 8 | - | 10 | - | 12 | - | 15 | - | ns |
| Address Valid to End of Write | t _{AW} | 6.5 | - | 8 | - | 12 | - | 15 | - | ns |
| Chip Enable to End of Write | t _{CW} | 6.5 | - | 8 | - | 12 | - | 15 | - | ns |
| Address Set-up Time | t _{AS} | 0 | - | 0 | - | 0 | - | 0 | - | ns |
| Write Pulse Width | t _{WP} | 6.5 | - | 8 | - | 9 | - | 10 | - | ns |
| Write Recovery Time | t _{WR} | 0 | - | 0 | - | 0 | - | 0 | - | ns |
| Data to Write Time Overlap | t _{DW} | 5 | - | 6 | - | 7 | - | 8 | - | ns |
| Data Hold from End of Write Time | t _{DH} | 0 | - | 0 | - | 0 | - | 0 | - | ns |
| Output Active from End of Write | t _{OW*} | 1.5 | - | 2 | - | 3 | - | 4 | - | ns |
| Write to Output in High Z | t _{WHZ*} | - | 5 | - | 6 | - | 7 | - | 8 | ns |

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